

Diode

Fast switching Emitter Controlled 3 diode chip SIDC81D120H8

**Data Sheet** 

# Industrial Power Control



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### Fast switching Emitter Controlled 3 diode chip

#### Features:

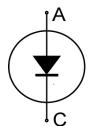
- 1200V Emitter Controlled technology 120µm chip
- Soft, fast switching
- Low reverse recovery charge
- Small temperature coefficient

#### Recommended for:

- Power modules
- Discrete devices

#### **Applications:**

- SMPS
- Resonant applications
- Drives



Chip Type	<b>V</b> <sub>R</sub>	<b>I</b> Fn	Die Size	Package
SIDC81D120H8	1200V	150A	9.00mm x 9.00mm	Sawn on foil

#### **Mechanical Parameters**

Die size		9.00 x 9.00			
Area total		81.00 mr			
Anode pad size		See chip drawing			
Silicon thickness		120			
Wafer size		200	mm		
Maximum possible chi	ps per wafer	315			
Passivation frontside		Photoimide			
Pad metal		3.2µm AlSiCu			
Backside metal		Ni Ag – system  To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process			
Die bond		Electrically conductive epoxy glue and soft solder			
Wire bond		Al, ≤ 500μm			
Reject ink dot size (va	lid for inked delivery form only)	Ø 0.65mm; max 1.2mm			
Storage environment (<6 months)	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 2			
	for open MBB bags	Acc. IEC 62258-3; Section 9.4 Storage Enviror			

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#### **Maximum Ratings**

In general, from reliability and lifetime point of view, the lower the operation junction temperature and/or the applied voltage, the greater the expected lifetime of any semiconductor device.

Not subject to production test, specified by design.

Parameter	Symbol	Value	Unit	
Repetitive peak reverse voltage, T <sub>vj</sub> =25°C	<b>V</b> RRM	1200	V	
Continuous forward current, limited by $T_{\rm vj\;max}$ <sup>1</sup>	lF	-		
Maximum repetitive forward current, $t_p$ limited by $T_{vjmax}$	<b>/</b> FRM	300	A	
Virtual junction temperature	$T_{ m vj}$	-40+175	°C	

#### Static Characteristics (tested on wafer), T<sub>vj</sub>=25°C

Danamatan	Cumbal	Conditions	Value			l lmi4
Parameter	Symbol Conditions		min.	typ.	max.	Unit
Reverse leakage current	<i>I</i> <sub>R</sub>	V <sub>R</sub> = 1200V	-	-	27.0	μA
Cathode-anode breakdown voltage	<b>V</b> BR	<i>I</i> <sub>R</sub> = 0.25mA	1200	-	-	V
Forward voltage drop	V <sub>F</sub>	/ <sub>F</sub> = 45A	1.06	1.29	1.41	

#### **Electrical Characteristics**

Not subject to production test, specified by design.

Parameter		Symbol	Condition	Value			Unit
- arameter		min.		typ.	max.	Oiii	
Forward voltage	$T_{\rm vj} = 25^{\circ}{\rm C}$	$V_{F}$	L - 150A	-	1.65	2.15	\ \/
drop	$T_{\rm vj} = 150^{\circ}{\rm C}$	VF	<i>I</i> <sub>F</sub> = 150A	-	1.65	-	V

#### **Further Electrical Characteristics**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

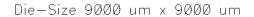
Application example	FS150R12KE3	Rev. 3.1
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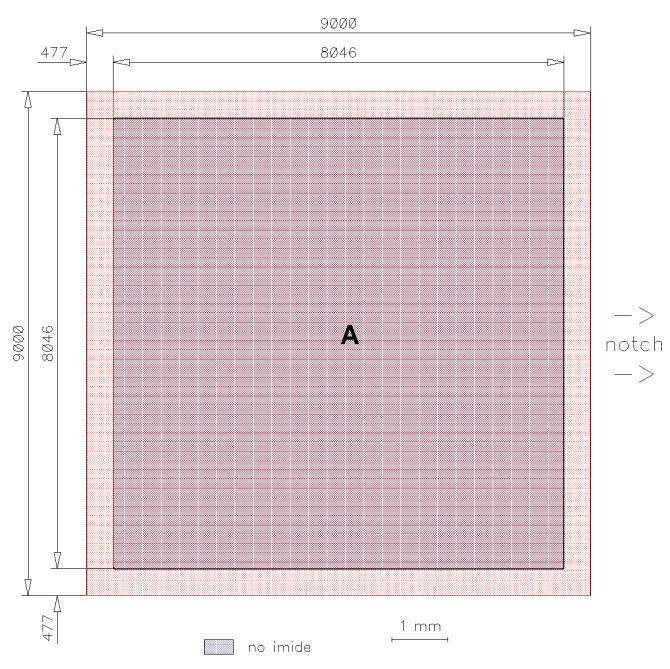
<sup>&</sup>lt;sup>1</sup> Depending on thermal properties of assembly.

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### **Chip Drawing**





**A** = Anode pad



#### **Bare Die Product Specifics**

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

#### **Description**

AQL 0.65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

#### **Revision History**

Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	30.12.2014
2.1	Editorial changes	14.10.2015
2.2	$I_{\text{F}}$ + $I_{\text{FRM}}$ conditions changed, $T_{\text{vj}}$ increased to 175°C, editorial changes	23.12.2021

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